

Notice of References Cited

Application/Control No.

10/733,562

Applicant(s)/Patent Under
Reexamination
TUIJN ET AL.

Examiner

John M. Frink

Art Unit

2142

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0009553 A1	01-2003	Benfield et al.	709/224
*	B	US-6,594,268 B1	07-2003	Aukia et al.	370/400
*	C	US-2002/0035604 A1	03-2002	Cohen et al.	709/205
*	D	US-2002/0062388 A1	05-2002	Ogier et al.	709/238
*	E	US-2003/0046134 A1	03-2003	Frolick et al.	705/8
*	F	US-2002/0184518 A1	12-2002	Foster et al.	713/200
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1093265 A2	04-2001	European Patent	NG et al.	H04L 12/56
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	European Search Report for EP 1 431 182 A1. April 16, 2004.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.